CoolMOS™ Power Transistor

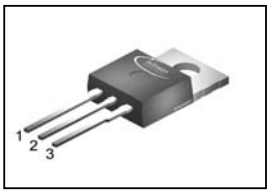
Features

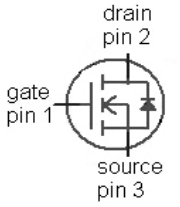
- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- High peak current capability
- Ultra low effective capacitances
- Extreme d*v*/d*t* rated
- Improved transconductance

Product Summary

V_{DS} @ $T_{j,max}$	650	V
$R_{DS(on),max}$	0.75	Ω
I_D	6.2	A

PG-TO220-3-1





Type	Package	Ordering Code	Marking
SPP06N60C3	PG-TO220-3-1	Q67040-S4629	06N60C3

Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	T_C=25 °C	6.2	A
		T_C=100 °C	3.9	
Pulsed drain current[1]	$I_{D,pulse}$	T_C=25 °C	18.6	
Avalanche energy, single pulse	E_{AS}	I_D=3.1 A, V_{DD}=50 V	200	mJ
Avalanche energy, repetitive t_{AR}[1),2)]	E_{AR}	I_D=6.2 A, V_{DD}=50 V	0.5	
Avalanche current, repetitive t_{AR}[1)]	I_{AR}		6.2	A
Drain source voltage slope	d*v*/d*t*	I_D=6.2 A, V_{DS}=480 V, T_j=125 °C	50	V/ns
Gate source voltage	V_{GS}	static	±20	V
	V_{GS}	AC (*f*>1 Hz)	±30	
Power dissipation	P_{tot}	T_C=25 °C	74	W
Operating and storage temperature	T_j, T_{stg}		-55 ... 150	°C

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}		-	-	1.7	K/W
Thermal resistance, junction - ambient	R_{thJA}	leaded	-	-	62	
	R_{thJA}	SMD version, device on PCB, minimal footprint	-	-	62	
		SMD version, device on PCB, 6 cm^2 cooling area[3)]	-	35	-	
Soldering temperature[4)]	T_{sold}	1.6 mm (0.063 in.) from case for 10 s	-	-	260	°C
Electrical characteristics, at T_j=25 °C, unless otherwise specified						
Static characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0 V, I_D=250 µA	600	-	-	V
Avalanche breakdown voltage	$V_{(BR)DS}$	V_{GS}=0 V, I_D=6.2 A	-	700	-	
Gate threshold voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_D=0.26 mA	2.1	3	3.9	
Zero gate voltage drain current	I_{DSS}	V_{DS}=600 V, V_{GS}=0 V, T_j=25 °C	-	0.1	1	µA
		V_{DS}=600 V, V_{GS}=0 V, T_j=150 °C	-	-	100	
Gate-source leakage current	I_{GSS}	V_{GS}=20 V, V_{DS}=0 V	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V_{GS}=10 V, I_D=3.9 A, T_j=25 °C	-	0.68	0.75	Ω
		V_{GS}=10 V, I_D=3.9 A, T_j=150 °C	-	1.82	-	
Gate resistance	R_G	f=1 MHz, open drain	-	1	-	
Transconductance	g_{fs}	$\|V_{DS}\|>2\|I_D\|R_{DS(on)max}$, I_D=3.9 A	-	5.6	-	S

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C_{iss}	V_{GS}=0 V, V_{DS}=25 V, f=1 MHz	-	620	-	pF
Output capacitance	C_{oss}		-	200	-	
Reverse transfer capacitance	C_{rss}		-	17	-	
Effective output capacitance, energy related[5)]	$C_{o(er)}$	V_{GS}=0 V, V_{DS}=0 V to 480 V	-	28	-	
Effective output capacitance, time related[6)]	$C_{o(tr)}$		-	47	-	
Turn-on delay time	$t_{d(on)}$	V_{DD}=480 V, V_{GS}=10 V, I_D=6.2 A, R_G=12 Ω	-	7	-	ns
Rise time	t_r		-	12	-	
Turn-off delay time	$t_{d(off)}$		-	52	-	
Fall time	t_f		-	10	-	
Gate Charge Characteristics						
Gate to source charge	Q_{gs}	V_{DD}=480 V, I_D=6.2 A, V_{GS}=0 to 10 V	-	3.3	-	nC
Gate to drain charge	Q_{gd}		-	12	-	
Gate charge total	Q_g		-	24	31	
Gate plateau voltage	$V_{plateau}$		-	5.5	-	V

[1)] Pulse width limited by maximum temperature $T_{j,max}$ only

[2)] Repetitive avalanche causes additional power losses that can be calculated as $P_{AV}=E_{AR}*f$.

[3)] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm^2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

[4)] Soldering temperature for TO263: 220 °C, reflow

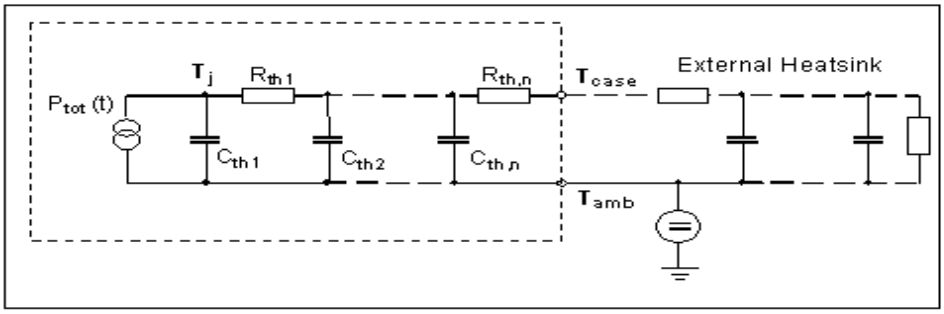
[5)] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

[6)] $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Reverse Diode						
Diode continuous forward current	I_S	T_C=25 °C	-	-	6.2	A
Diode pulse current	$I_{S,pulse}$		-	-	18.6	
Diode forward voltage	V_{SD}	V_{GS}=0 V, I_F=6.2 A, T_j=25 °C	-	0.97	1.2	V
Reverse recovery time	t_{rr}	V_R=480 V, I_F=I_S, di_F/dt=100 A/µs	-	400	-	ns
Reverse recovery charge	Q_{rr}		-	3.5	-	µC
Peak reverse recovery current	I_{rrm}		-	25	-	A

Typical Transient Thermal Characteristics

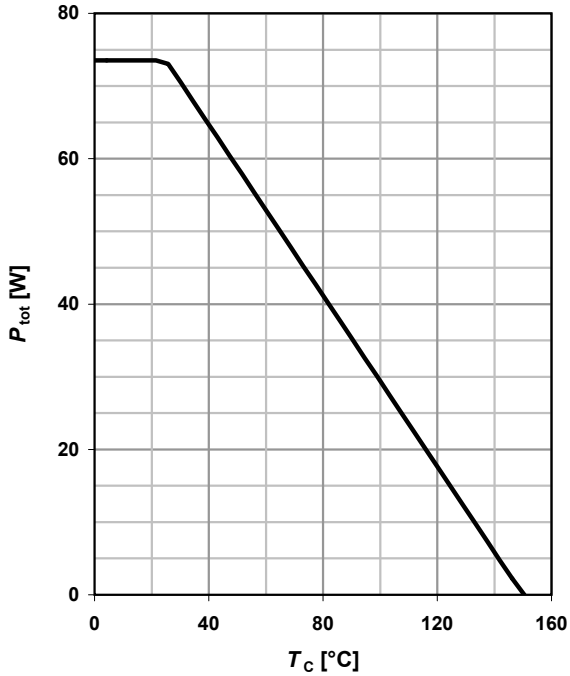
Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
R_{th1}	0.0325	K/W	C_{th1}	0.0000502	Ws/K
R_{th2}	0.0448		C_{th2}	0.000303	
R_{th3}	0.251		C_{th3}	0.000428	
R_{th4}	0.31		C_{th4}	0.00243	
R_{th5}	0.301		C_{th5}	0.00526	
			C_{th6}	1.09[7)]	



[7)] C_{th6} models the additional heat capacitance of the package in case of non-ideal cooling. It is not needed if R_{thCA}=0 K/W.

1 Power dissipation

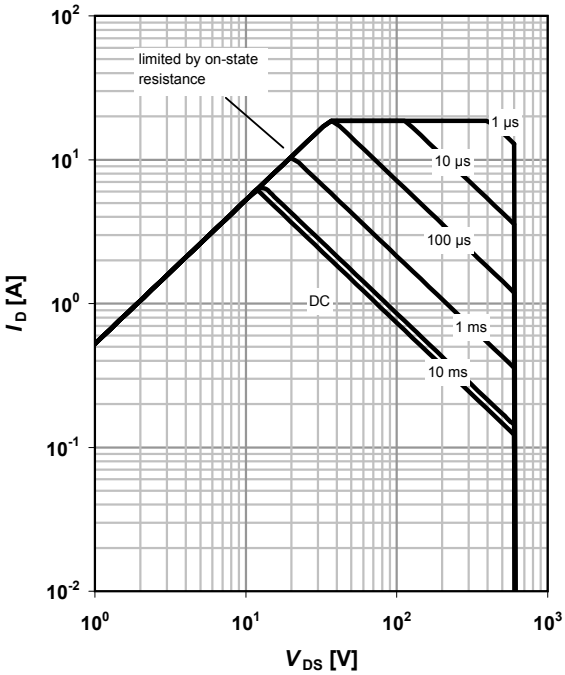
$P_{tot}=f(T_C)$



2 Safe operating area

$I_D=f(V_{DS})$; $T_C=25$ °C; $D=0$

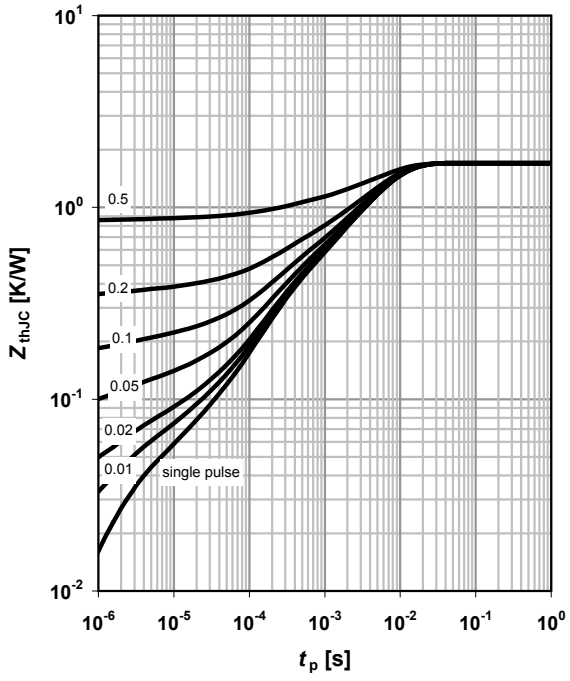
parameter: t_p



3 Max. transient thermal impedance

$I_D=f(V_{DS})$; $T_j=25$ °C

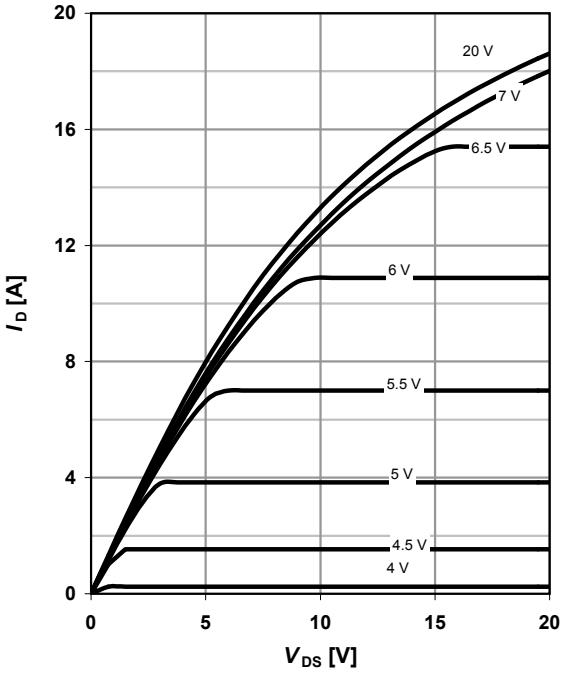
parameter: $D=t_p/T$



4 Typ. output characteristics

$I_D=f(V_{DS})$; $T_j=25$ °C

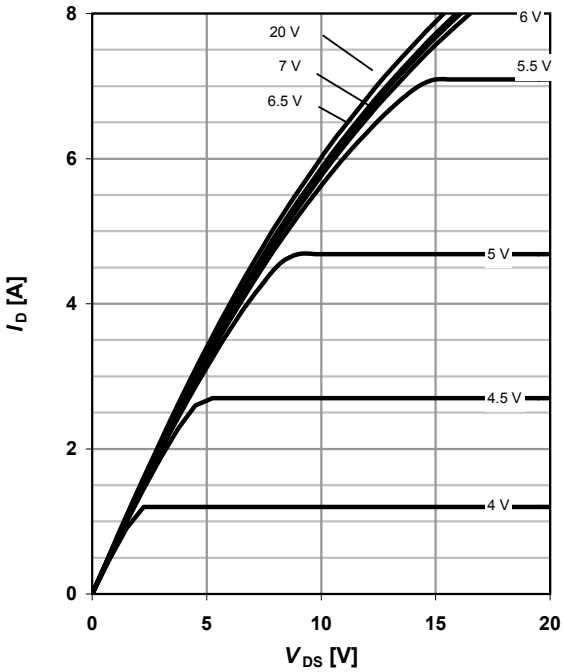
parameter: V_{GS}



5 Typ. output characteristics

I_D=f(V_{DS}); T_j=150 °C

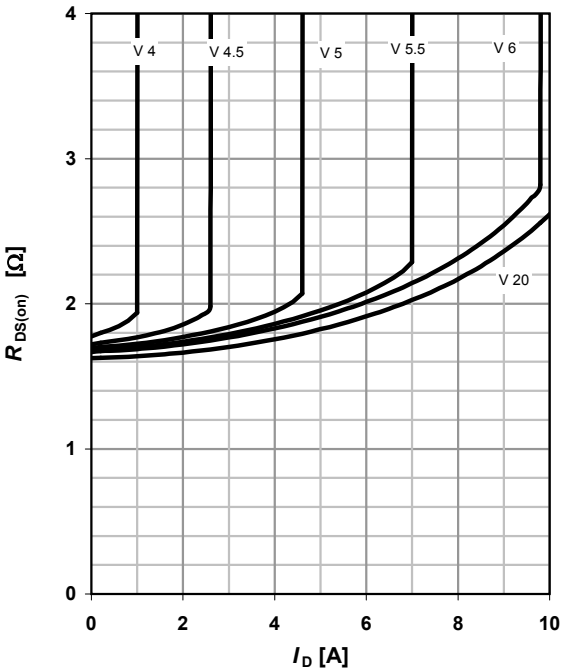
parameter: V_{GS}



6 Typ. drain-source on-state resistance

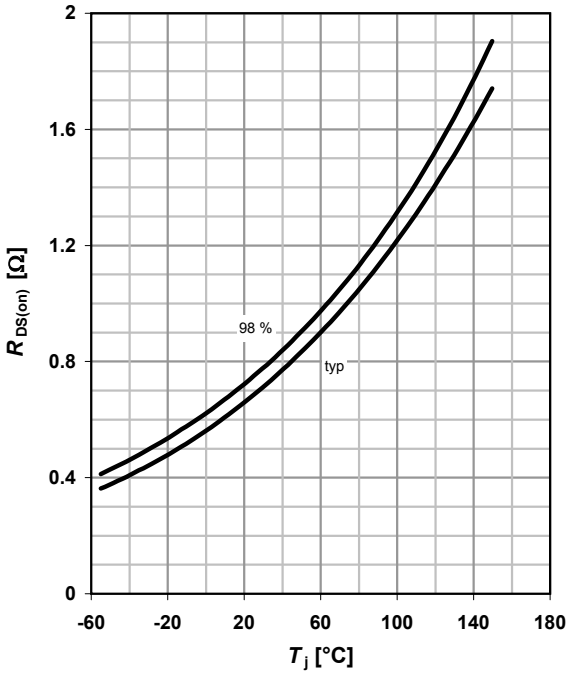
$R_{DS(on)}$=f(I_D); T_j=150 °C

parameter: V_{GS}



7 Drain-source on-state resistance

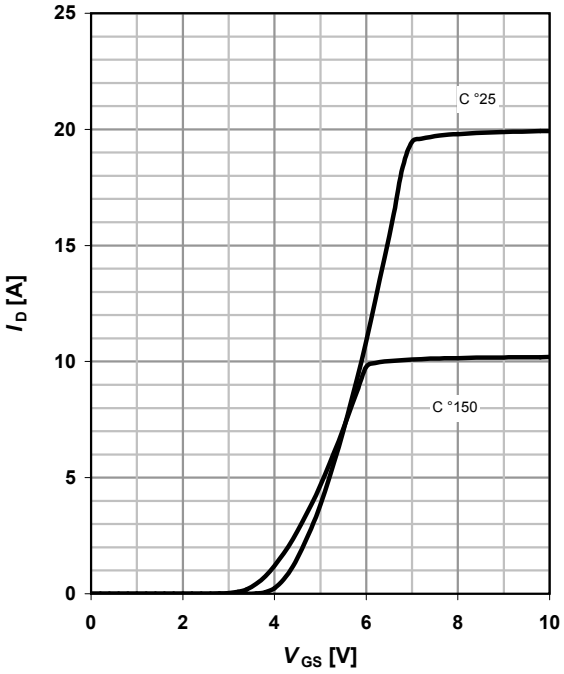
$R_{DS(on)}$=f(T_j); I_D=3.9 A; V_{GS}=10 V



8 Typ. transfer characteristics

I_D=f(V_{GS}); $|V_{DS}|>2|I_D|R_{DS(on)max}$

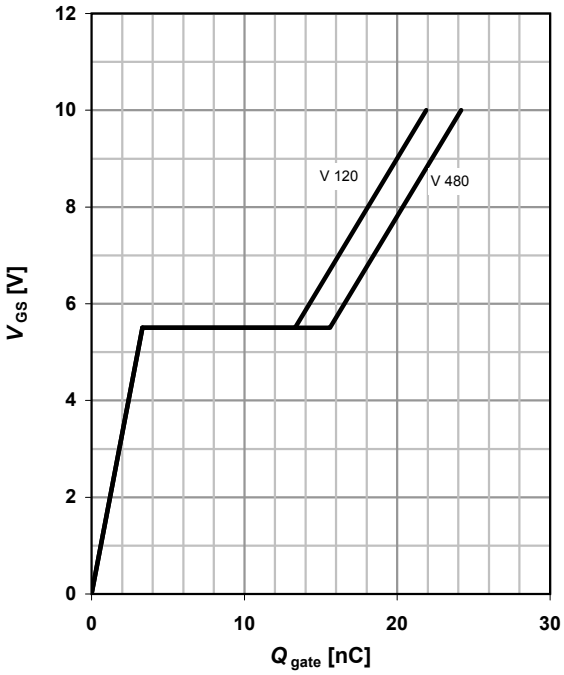
parameter: T_j



9 Typ. gate charge

V_{GS}=f(Q_{gate}); I_D=6.2 A pulsed

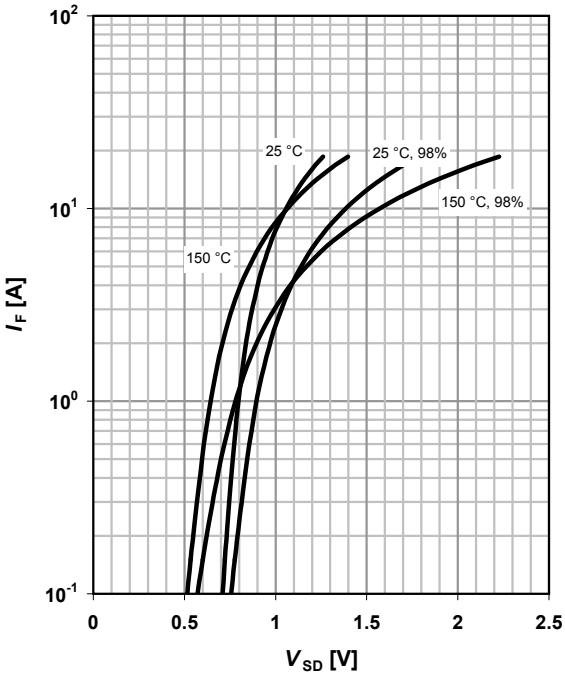
parameter: V_{DD}



10 Forward characteristics of reverse diode

I_F=f(V_{SD})

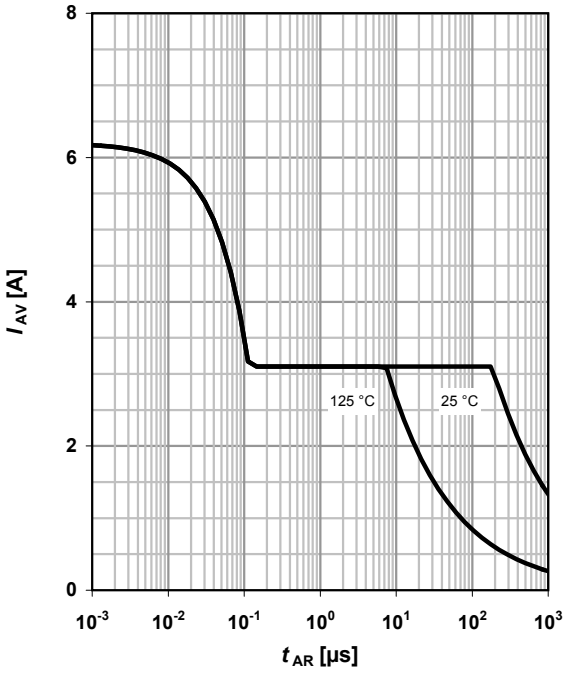
parameter: T_j



11 Avalanche SOA

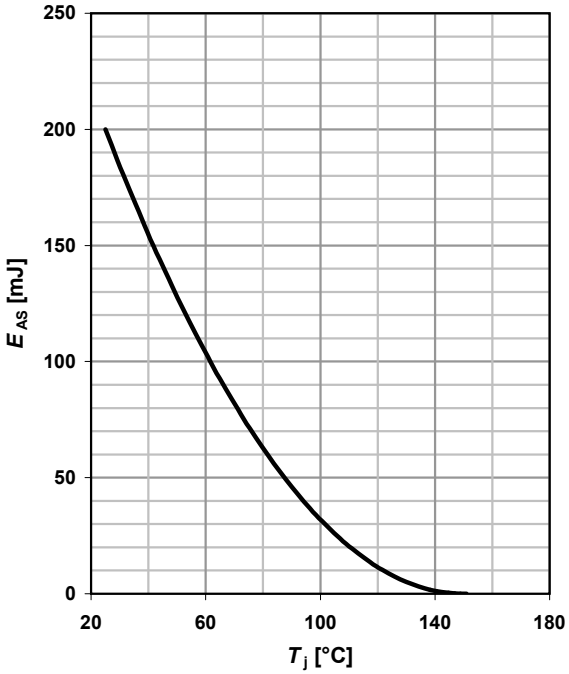
I_{AR}=f(t_{AR})

parameter: $T_{j(start)}$



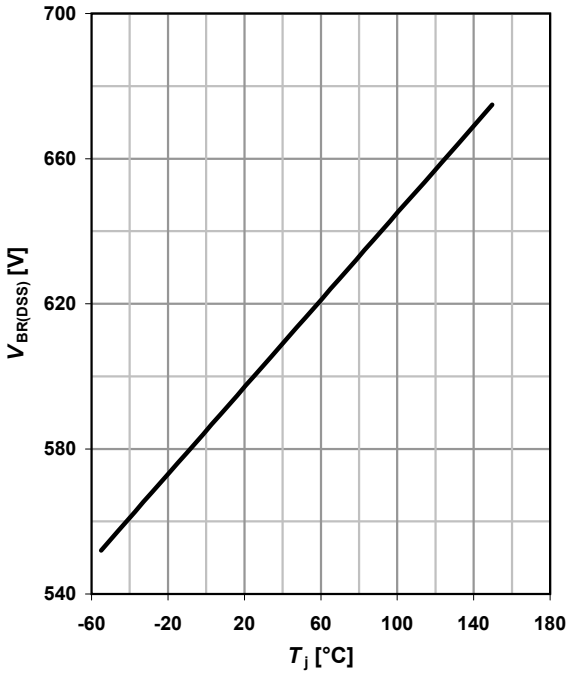
12 Avalanche energy

E_{AS}=f(T_j); I_D=3.1 A; V_{DD}=50 V



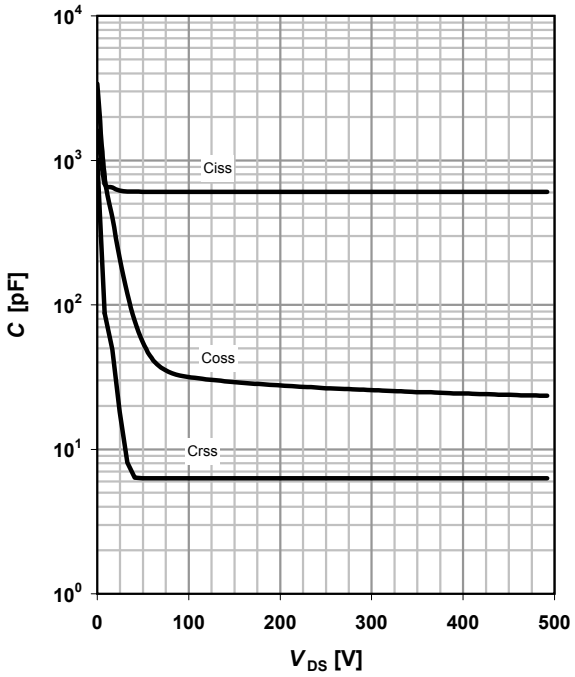
13 Drain-source breakdown voltage

$V_{BR(DSS)}$=f(T_j); I_D=0.25 mA



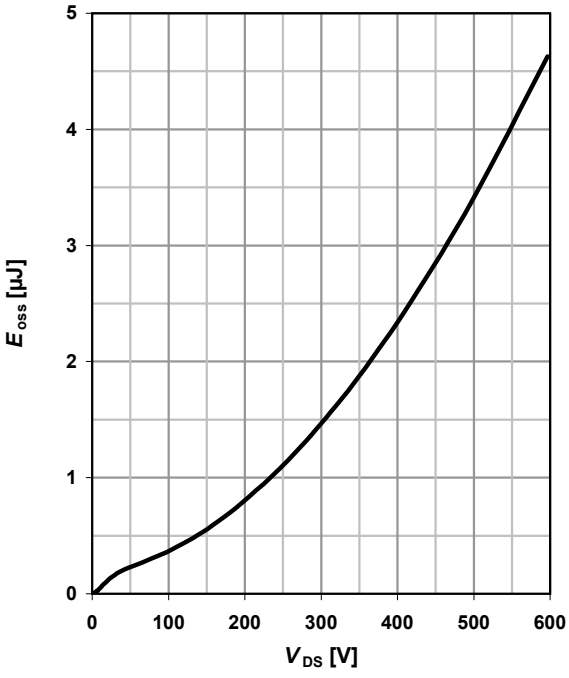
14 Typ. capacitances

C=f(V_{DS}); V_{GS}=0 V; f=1 MHz

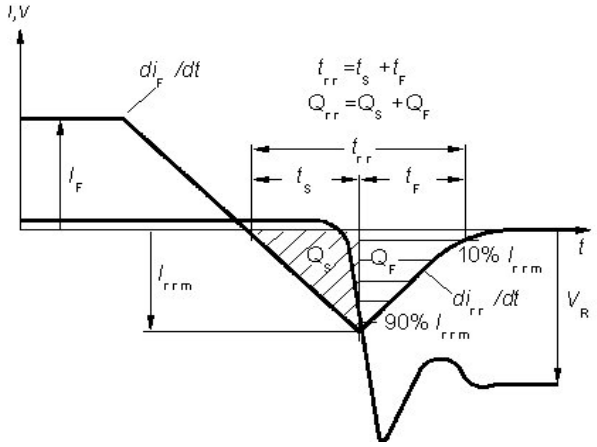


15 Typ. C_{oss} stored energy

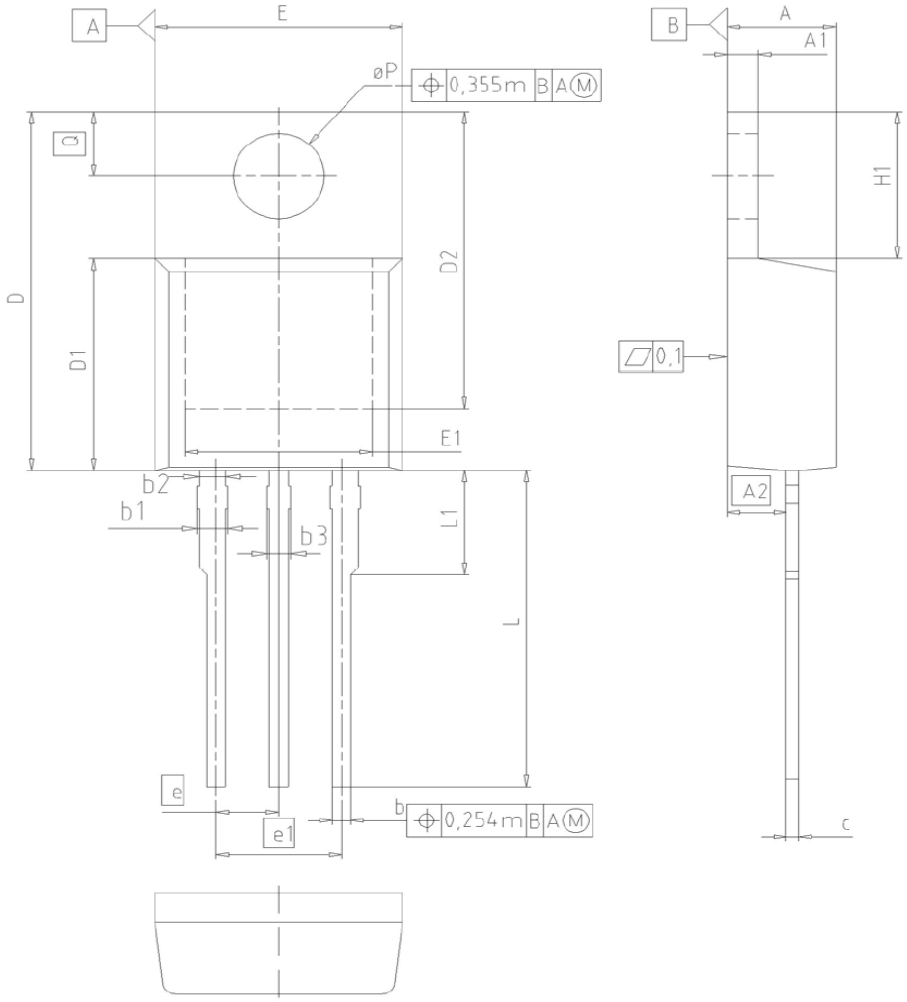
E_{oss}= f(V_{DS})



Definition of diode switching characteristics



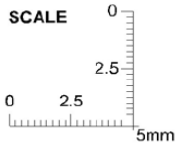
PG-TO220-3-1



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øP	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

DOCUMENT NO.
Z8B00003318

SCALE



EUROPEAN PROJECTION

ISSUE DATE
23-08-2007

REVISION
05

Published by
Infineon Technologies AG
Bereich Kommunikation
St.-Martin-Straße 53
D-81541 München

Attention please!
The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information
For further information on technology, delivery terms and conditions and prices, please contact your nearest Infineon Technologies office in Germany or our Infineon Technologies representatives worldwide (see address list).

Warnings
Due to technical requirements, components may contain dangerous substances.
For information on the types in question, please contact your nearest Infineon Technologies office.

Infineon Technologies' components may only be used in life-support devices or systems with the expressed written approval of Infineon Technologies if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.